AMENDMENTS IN THE SPECIFICATION

Please replace paragraph [0025] with the following:

As depicted in Figure 4, the self-test system 48 includes a random digital sequence generator 52 which issues a series of digital "1" and "0" bits in a random sequence. A suitable random digital sequence generator 52, for example, takes the form of a linear feedback shift register to generate the random sequence of digital bits. The random output sequence of digital bits from the generator 52 is furnished to an activate circuit 54. In one embodiment, the random digital sequence generator 52 and the activate circuit 54 are included within a single component, referred to as the activator 51. As will be set forth, the activate circuit 54 includes a time adjust system 56 (Figure 5) which, on receipt of signals on line 50 introduces time delay or jitter in the data windows. At such times, the activate circuit 54 sends test data in the form of the random digital sequence from generator 52, but in data windows or eyes which are delayed in the opening or advanced in their closing, or both, like the data windows 14 of Figure 2.

Please replace paragraph [0035] with the following:

Figure 5 in the drawings depicts a preferred embodiment of the activate circuit 54. The incoming stream of bits, whether SYSTEM DATA or a random series of bits from the random sequence generator 52, is fed to each of a pair of latches 63 and 65. The latches 63 and 65 are set to operate and store alternating bits, "ODD" and "EVEN", in the sequence of bits received from the generator 52. Latch 63 is termed an even bit latch and latch 65 is termed an odd bit latch. The latches 63 and 65 are connected to a multiplexer 66 where the alternating bits are recombined. Thus, either SYSTEMDATA SYSTEM DATA or serial test data in the recombined form of the original random bit sequence from the generator 52, is presented to the multiplexer 60. The multiplexer 60 allows the bit sequence to pass to an amplifier of driver 62 and to an amplifier in driver 64.

Please replace paragraph [0037] *with the following:*

A decode gating circuit 80 is connected to the outputs of each of the four latches [[62]] 63, [[64]] 65, 74 and 76. The decode gating circuit 80 is configured to indicate when the

selected sequence of bits described above is present. As has been set forth, in the preferred embodiment, the desired sequence is the presence of either four consecutive "1" bits or 1111, or four consecutive "0" bits, or 0000, in the output from the generator 52. Thus, in the preferred embodiment a logic element or function 82 detects the presence of the 1111 bits in the four latches and forms a FOUR ONES signal at its output. The FOUR ONES output of logic element 82 is furnished to a stretcher or delay circuit 83 formed by a latch 83A, a delay element 83B having a delay of 1/4 of a bit period, and an OR element or function 83C. The latch 83A delays the output of logic 82 by 2 bit periods.

Please replace paragraph [0041] *with the following:*

The outputs from the logic function 98, 100 and 102 are furnished to an OR logic function 104 which in turn is connected to the multiplexor 60. The multiplexor 60 is arranged to normally pass serial data, as has been set forth. In the event of an activation indication from line 50 to add jitter, the multiplexor 60 instead allows signals to pass to an amplifier in drivers [[70]] 62 and [[72]] 64 according to the logic functions performed in the gating circuit 80. The operation of the logic functions in gating circuit 80 may be implemented by individual logic elements as shown schematically in the drawings or in an application specific integrating circuit or ASIC or some other arrangement according to the following logic equation: